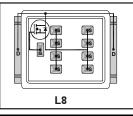


IRF7779L2PbF

- DirectFET™ Power MOSFET ②
- Typical values (unless otherwise specified)

V _{DSS}	V _{GS}	R _{DS(on)}
150V min	±20V max	$9.0 \text{m}\Omega$ @ 10V
$Q_{g tot}$	\mathbf{Q}_{gd}	$V_{gs(th)}$
97nC	33nC	4.0V





• RoHS Compliant, Halogen Free ①

- Lead-Free (Qualified up to 260°C Reflow)
- Ideal for High Performance Isolated Converter Primary Switch Socket
- Optimized for Synchronous Rectification
- Low Conduction Losses
- High Cdv/dt Immunity
- Low Profile (<0.7mm)
- Dual Sided Cooling Compatible ①
- Compatible with existing Surface Mount Techniques ①
- Industrial Qualified

Applicable DirectFET Outline and Substrate Outline ①

SB	SC		M2	M4	L4	L6	L8	

Description

The IRF7779L2TR/TR1PbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has a footprint smaller than a D²PAK and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems.

The IRF7779L2TR/TR1PbF is optimized for high frequency switching and synchronous rectification applications. The reduced total losses in the device coupled with the high level of thermal performance enables high efficiency and low temperatures, which are key for system reliability improvements, and makes this device ideal for high performance power converters.

Ordereble next number	Deekers Ture	Standard Pa	ck	Note
Orderable part number	Package Type	Form	Quantity	Note
IRF7779L2TRPbF	DirectFET2 Large Can	Tape and Reel	4000	"TR" suffix
IRF7779L2TR1PbF	DirectFET2 Large Can	Tape and Reel	1000	"TR1" suffix EOL notice # 264

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	150	V
V _{GS}	Gate-to-Source Voltage	±20	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) @	67	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) @	47	Α
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) 3	11	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited) @	375	
I _{DM}	Pulsed Drain Current ⑤	270	
E _{AS}	Single Pulse Avalanche Energy ®	270	mJ
lab.	Avalanche Current ⑤	40	Α

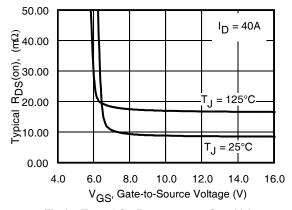


Fig 1. Typical On-Resistance vs. Gate Voltage

Notes:

- $\ensuremath{\mathbb{O}}$ Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.

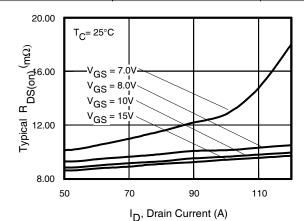


Fig 2. Typical On-Resistance vs. Drain Current

- ④ T_C measured with thermocouple mounted to top (Drain) of part.
- S Repetitive rating; pulse width limited by max. junction temperature.
- © Starting $T_J = 25$ °C, L = 0.33mH, $R_G = 25\Omega$, $I_{AS} = 40$ A.



Static @ $T_J = 25$ °C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	150			٧	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.13		V/°C	Reference to 25°C, I _D = 2mA
Static Drain-to-Source On-Resistance		9.0	11	mΩ	V _{GS} = 10V, I _D = 40A ⑦
Gate Threshold Voltage	3.0	4.0	5.0	٧	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Gate Threshold Voltage Coefficient		-15		mV/°C	
Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 150V, V_{GS} = 0V$
			250	1	$V_{DS} = 120V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
Gate-to-Source Reverse Leakage			-100	Ī	V _{GS} = -20V
Forward Transconductance	83			S	$V_{DS} = 50V, I_{D} = 40A$
Total Gate Charge		97	150		
Pre-Vth Gate-to-Source Charge		27		Ī	$V_{DS} = 75V$
Post-Vth Gate-to-Source Charge		6.9		nC	V _{GS} = 10V
Gate-to-Drain Charge		33	50	Ī	$I_D = 40A$
Gate Charge Overdrive		30		1	See Fig. 9
Switch Charge (Q _{gs2} + Q _{gd})		40		Ī	
Output Charge		39		nC	$V_{DS} = 16V, V_{GS} = 0V$
Gate Resistance		1.5		Ω	
Turn-On Delay Time		16			V _{DD} = 75V, V _{GS} = 10V ⑦
Rise Time		19			$I_D = 40A$
Turn-Off Delay Time		36		ns	$R_G=1.8\Omega$
Fall Time		12			
Input Capacitance		6660			$V_{GS} = 0V$
Output Capacitance		840		pF	$V_{DS} = 25V$
Reverse Transfer Capacitance		180			f = 1.0MHz
Output Capacitance		5620			$V_{GS} = 0V, V_{DS} = 1.0V, f=1.0MHz$
Output Capacitance		400			$V_{GS} = 0V, V_{DS} = 120V, f=1.0MHz$
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Total Gate Charge Pre-Vth Gate-to-Source Charge Post-Vth Gate-to-Source Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Gate Resistance Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current —— Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Total Gate Charge Pre-Vth Gate-to-Source Charge Post-Vth Gate-to-Source Charge Gate-to-Drain Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Gate Resistance Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Output Capacitance —— Output Capacitance	Drain-to-Source Breakdown Voltage 150 — Breakdown Voltage Temp. Coefficient — 0.13 Static Drain-to-Source On-Resistance — 9.0 Gate Threshold Voltage 3.0 4.0 Gate Threshold Voltage Coefficient — -15 Drain-to-Source Leakage Current — — — — — Gate-to-Source Forward Leakage — — Gate-to-Source Forward Leakage — — Forward Transconductance 83 — Forward Transconductance 83 — Forward Transconductance 83 — Pre-Vth Gate-to-Source Charge — 97 Pre-Vth Gate-to-Source Charge — 6.9 Gate Charge Overdrive — 30 Switch Charge (Q _{gs2} + Q _{gd}) — 40 Output Charge — 39 Gate Resistance — 1.5 Turn-On Delay Time — 16 Rise Time — 12 Input Ca	Drain-to-Source Breakdown Voltage 150 — — Breakdown Voltage Temp. Coefficient — 0.13 — Static Drain-to-Source On-Resistance — 9.0 11 Gate Threshold Voltage 3.0 4.0 5.0 Gate Threshold Voltage Coefficient — -15 — Drain-to-Source Leakage Current — — 20 — — 250 Gate-to-Source Leakage Current — — 250 Gate-to-Source Forward Leakage — — 100 Gate-to-Source Reverse Leakage — — 100 Forward Transconductance 83 — — Total Gate Charge — 97 150 Pre-Vth Gate-to-Source Charge — 97 150 Pre-Vth Gate-to-Source Charge — 6.9 — Gate Charge Overdrive — 33 50 Gate Charge Overdrive — 30 — Switch Charge (Q _{gs2} + Q _{gd}) — 40	Drain-to-Source Breakdown Voltage 150 — V Breakdown Voltage Temp. Coefficient — 0.13 — V/°C Static Drain-to-Source On-Resistance — 9.0 11 mΩ Gate Threshold Voltage 3.0 4.0 5.0 V Gate Threshold Voltage Coefficient — -15 — mV/°C Drain-to-Source Leakage Current — -15 — mV/°C Gate-to-Source Leakage Current — 20 μA — — 250 nA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Forward Transconductance 83 — — S Total Gate Charge — 97 150 pre-Vth Gate-to-Source Charge — 97 150 pre-Vth Gate-to-Source Charge — 27 — nC gate-to-Drain Charge — 33 50 — se nC gate

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			67		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			270		integral reverse
	(Body Diode) ⑤					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 40A, V_{GS} = 0V$ ②
t _{rr}	Reverse Recovery Time		110	170	ns	$T_J = 25^{\circ}C, I_F = 40A, V_{DD} = 75V$
Q _{rr}	Reverse Recovery Charge		510	770	nC	di/dt = 100A/µs ⑦

Notes:

⑤ Repetitive rating; pulse width limited by max. junction temperature.

 $[\]ensuremath{{\bigcirc}}$ Pulse width $\le 400 \mu s;$ duty cycle $\le 2\%.$



Absolute Maximum Ratings

	Parameter	Max.	Units
P _D @T _C = 25°C	Power Dissipation ④	125	W
P _D @T _C = 100°C	Power Dissipation	63	\exists
P _D @T _A = 25°C	Power Dissipation ①	3.3	\exists
T _P	Peak Soldering Temperature	270	°C
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient ③		45	
$R_{\theta JA}$	Junction-to-Ambient ®	12.5		
$R_{\theta JA}$	Junction-to-Ambient	20		°C/W
$R_{\theta J\text{-Can}}$	Junction-to-Can ⊕®		1.2	
$R_{\theta J\text{-PCB}}$	Junction-to-PCB Mounted		0.5	

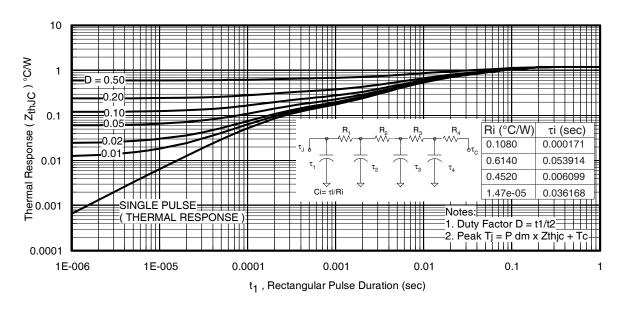


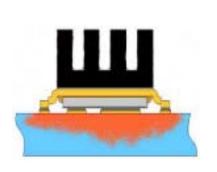
Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Case @

Notes:

- 3 Surface mounted on 1 in. square Cu board, steady state.
- ④ T_C measured with thermocouple incontact with top (Drain) of part.
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- $^{\circledR}$ R $_{\theta}$ is measured at T_{J} of approximately 90°C.



3 Surface mounted on 1 in. square Cu board (still air).





 Mounted on minimum footprint full size board with metalized back and with small clip heatsink. (still air)

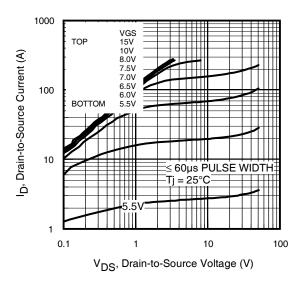


Fig 4. Typical Output Characteristics

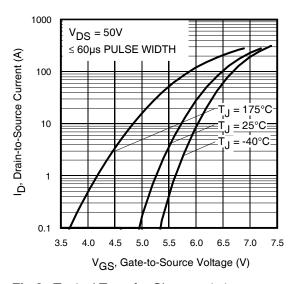


Fig 6. Typical Transfer Characteristics

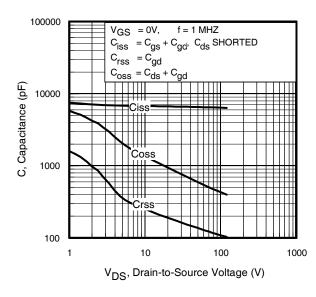


Fig 8. Typical Capacitance vs.Drain-to-Source Voltage

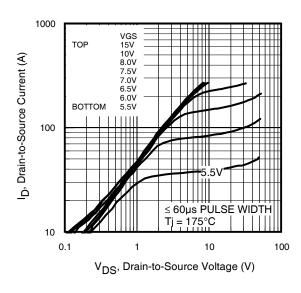


Fig 5. Typical Output Characteristics

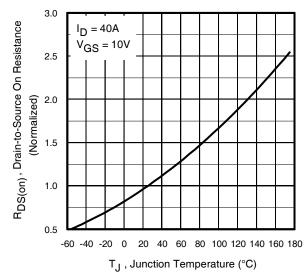


Fig 7. Normalized On-Resistance vs. Temperature

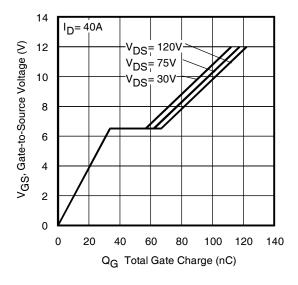


Fig 9. Typical Total Gate Charge vs Gate-to-Source Voltage



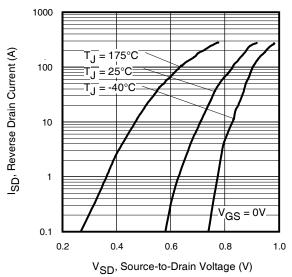


Fig 10. Typical Source-Drain Diode Forward Voltage

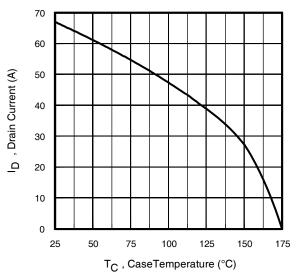


Fig 12. Maximum Drain Current vs. Case Temperature

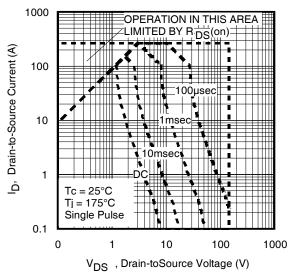


Fig11. Maximum Safe Operating Area

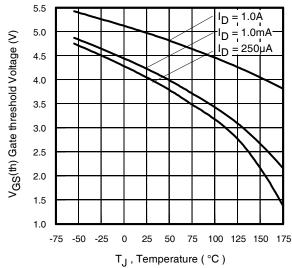


Fig 13. Typical Threshold Voltage vs. Junction Temperature

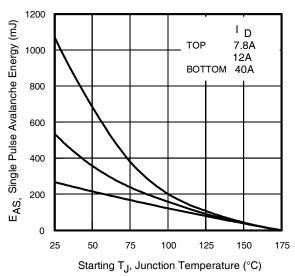


Fig 14. Maximum Avalanche Energy Vs. Drain Current



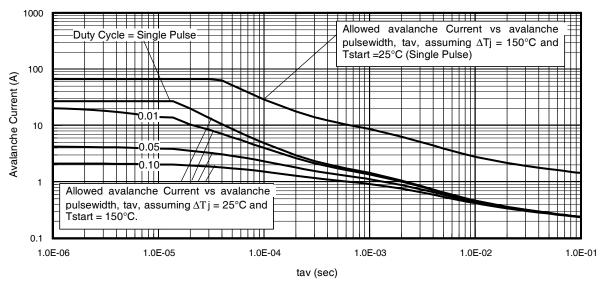


Fig 15. Typical Avalanche Current Vs. Pulsewidth

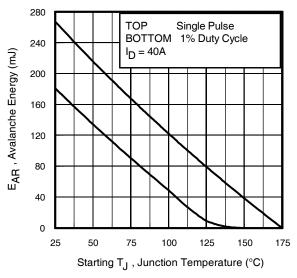


Fig 16. Maximum Avalanche Energy Vs. Temperature

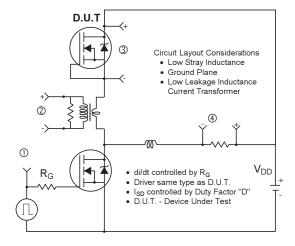
Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

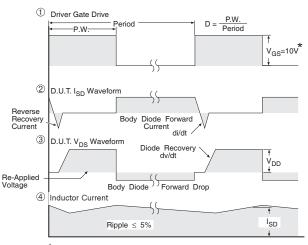
- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 19a, 19b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{aV}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{a} \end{split}$$





* V_{GS} = 5V for Logic Level Devices

Fig 17. Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs



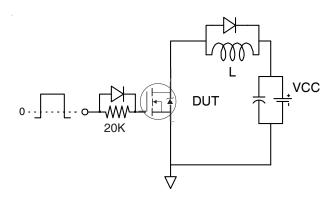


Fig 18a. Gate Charge Test Circuit

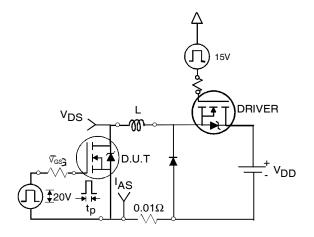


Fig 19a. Unclamped Inductive Test Circuit

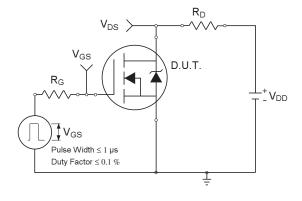


Fig 20a. Switching Time Test Circuit

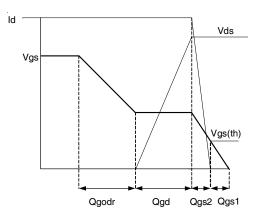


Fig 18b. Gate Charge Waveform

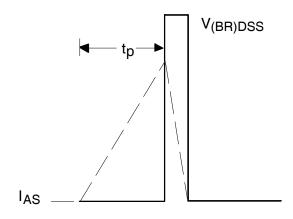


Fig 19b. Unclamped Inductive Waveforms

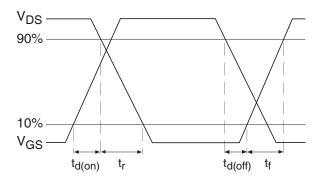
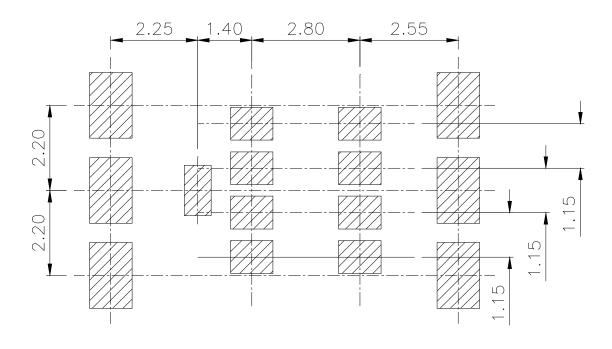


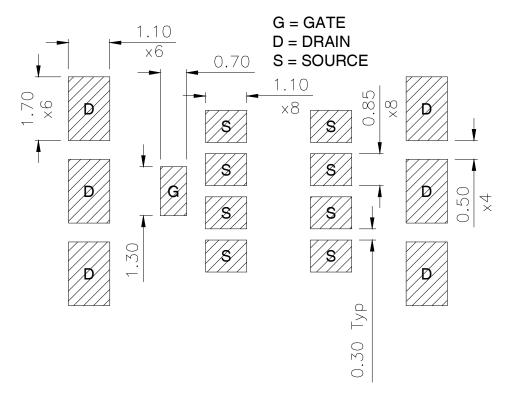
Fig 20b. Switching Time Waveforms



DirectFET™ Board Footprint, L8 (Large Size Can).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations



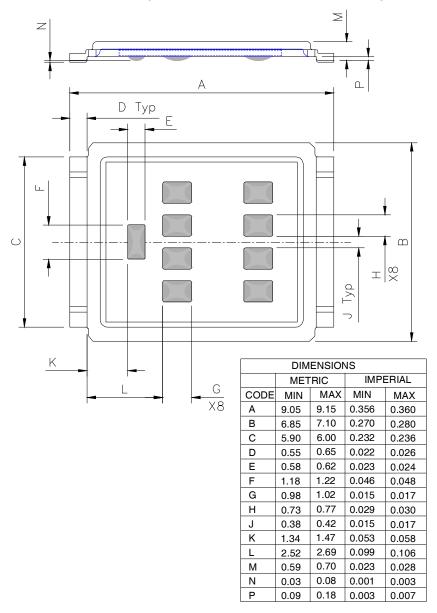


Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/

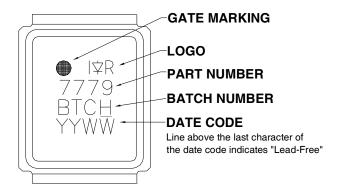


DirectFET™ Outline Dimension, L8 Outline (LargeSize Can).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations



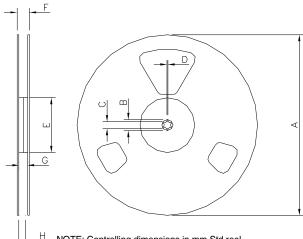
DirectFET™ Part Marking



Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/



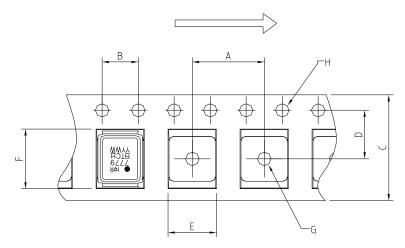
DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4000 parts. (ordered as IRF7779L2PBF).

REEL DIMENSIONS				
S	TANDARI	OPTION	I (QTY 40	00)
	ME	TRIC	IMP	ERIAL
CODE	MIN	MAX	MIN	MAX
Α	330.0	N.C	12.992	N.C
В	20.2	N.C	0.795	N.C
С	12.8	13.2	0.504	0.520
D	1.5	N.C	0.059	N.C
Е	100.0	N.C	3.937	N.C
F	N.C	22.4	N.C	0.889
G	16.4	18.4	0.646	0.724
Н	15.9	18.4	0.626	0.724

LOADED TAPE FEED DIRECTION



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS						
	ME	TRIC	IMP	ERIAL		
CODE	MIN	MAX	MIN	MAX		
Α	11.90	12.10	0.469	0.476		
В	3.90	4.10	0.154	0.161		
С	15.90	16.30	0.626	0.642		
D	7.40	7.60	0.291	0.299		
Е	7.20	7.40	0.284	0.291		
F	9.90	10.10	0.390	0.398		
G	1.50	NC	0.059	NC		
Н	1.50	1.60	0.059	0.063		

Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/



Qualification Information[†]

Qualification information						
Qualification level		Industrial ^{††}				
	(per JEDEC	(per JEDEC JESD47F ^{†††} guidelines)				
		Comments: This family of products has passed JEDEC's Industrial qualification. IR's Consumer qualification level is granted by extension of the higher Industrial level.				
Moisture Sensitivity Level	DFET2	MSL1				
		(per JEDEC J-STD-020D ^{†††})				
RoHS Compliant	Yes					

- † Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability
- †† Higher qualification ratings may be available should the user have such requirements.

 Please contact your International Rectifier sales representative for further information:

 http://www.irf.com/whoto-call/salesrep/
- ††† Applicable version of JEDEC standard at the time of product release.

Revision History

	Revision History	
Date		Comments
	5/6/2014	• Updated ordering information to reflect the End-Of-life (EOL) of the mini-reel option (EOL notice #264).
		Updated data sheet based on corporate template.



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